Search Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	ler	
10/564,152	NISHINO, HISANORI	NISHINO, HISANORI	
Examiner	Art Unit		
David E. Bochna	3679		

SEARCHED				
Class	Subclass	Date	Examiner	
285	133.3	1/2/2008	DB	
	133.5			
	133.6			
	133.11			
	133.21			
	133.4			
			·	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			·	
*	<u> </u>			

(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
_		
·		
•		
	*	
	i	